

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination CHEREPINSKY ET AL.	
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**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-			
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**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	Cutler et al. "High-Throughput Variation Detection and Genotyping Using Microarrays," Genome Research (2001) Volume 11, pages 1913-1925.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))  
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